MATERIALS RESEARCH SOCIETY
SYMPOSIUM PROCEEDINGS VOLUME 1474

Local Probing Techniques and In-Situ Measurements in Materials Science

April 9-13, 2012
San Francisco, California, USA

Printed from e-media with permission by:

Curran Associates, Inc.
57 Morehouse Lane
Red Hook, NY 12571
www.proceedings.com

ISBN: 978-1-62748-267-7

Cambridge University Press
Cambridge, New York, Melbourne, Madrid, Cape Town,
Singapore, São Paulo, Delhi, Tokyo, Mexico City

Cambridge University Press
32 Avenue of the Americas, New York, NY 10013-2473, USA
www.cambridge.org

Materials Research Society
506 Keystone Drive, Warrendale, PA 15086
www.mrs.org

CODEN: MRSPDH

ISBN: 978-1-62748-267-7

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